

Abstract Submitted  
for the MAR14 Meeting of  
The American Physical Society

**Interface effect on multilayer tungsten disulfide device caused by substrate and water molecule** XUE LIU, Tulane University, YUN LING, Jiangsu University, JIN HU, CHUNLEI YUE, ZHIQIANG MAO, JIANG WEI, Tulane University — We investigated field effect transistor (FET) device made of multilayered WS<sub>2</sub> with Poly(methyl methacrylate) (PMMA) as the dielectric layer. The device was fabricated using shadow mask evaporation to improve contact. Comparing to the same FET with SiO<sub>2</sub> dielectric layer, PMMA-WS<sub>2</sub> device shows an excellent on-off ratio (up to 6 orders magnitude), an easily induced ambipolar behavior and a significantly reduced hysteresis at high gate voltage region during the gate sweep. Furthermore, we discovered that the water molecule absorbed onto the WS<sub>2</sub> surface depletes the extra charge carriers at the neutrality point and transforms the device into insulating state at room temperature. In addition, we found that the effect caused by water absorption is reversible.

Xue Liu  
Tulane Univ

Date submitted: 15 Nov 2013

Electronic form version 1.4